

Hierarchically hollow structured $\text{NiCo}_2\text{S}_4@\text{NiS}$ for high-performance flexible hybrid supercapacitors

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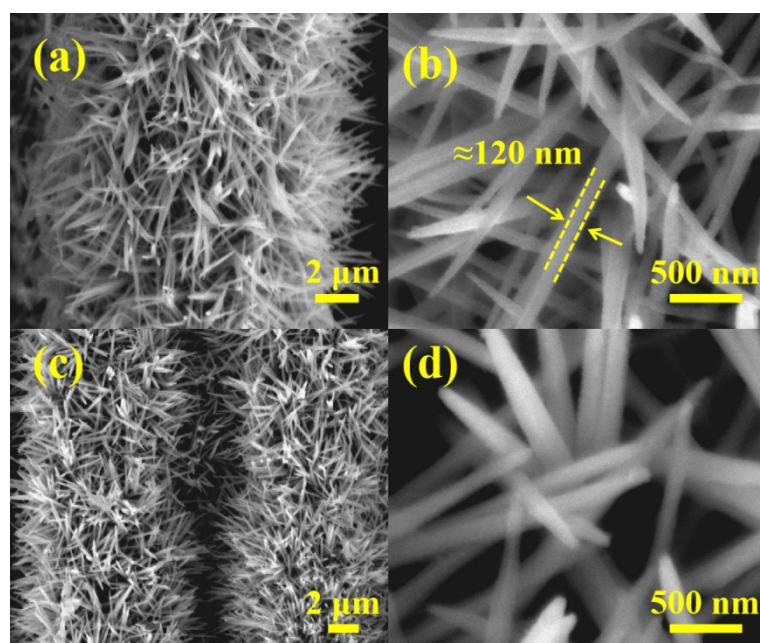


Fig. S1 SEM images. Low and high magnifications of NiCo -DHs nanoneedle arrays (a,b) and NiCo_2S_4 nanoneedle arrays (c,d).

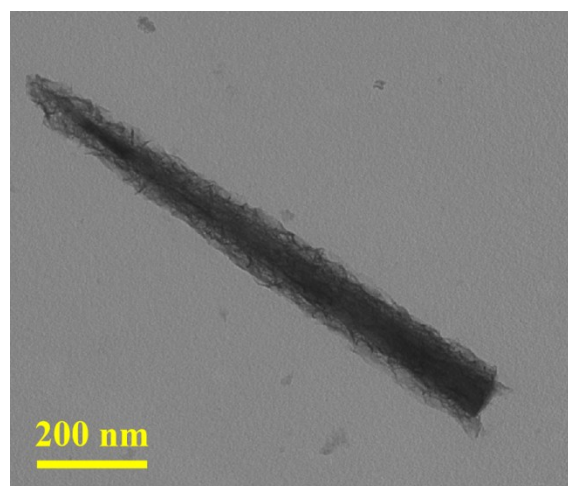


Fig. S2 TEM image of single root NiCo-DHs@Ni(OH)₂.

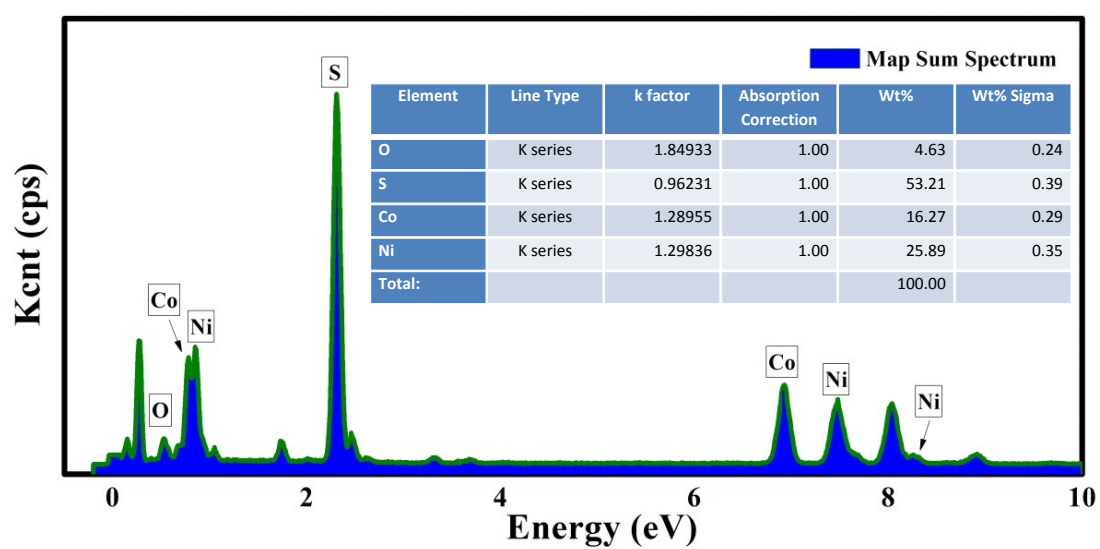


Fig. S3 EDS spectrum of NiCo₂S₄@NiS/CF.

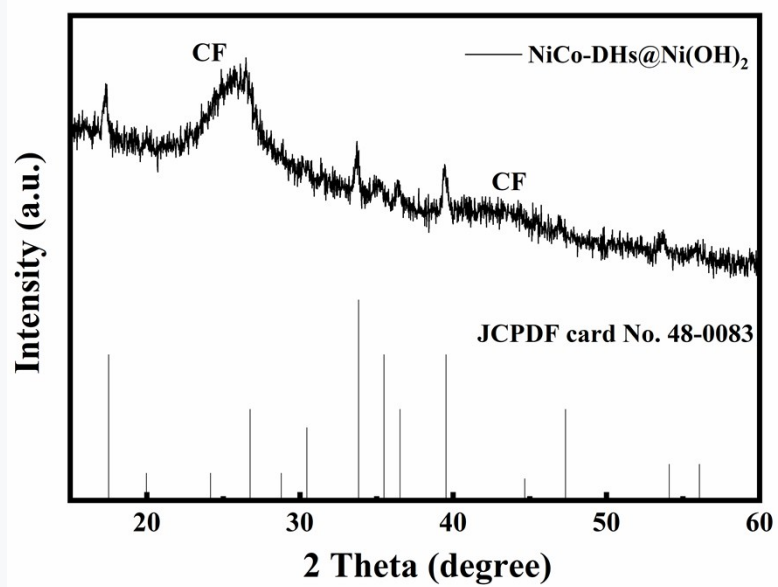


Fig. S4 XRD spectrum of the NiCo-DHs@Ni(OH)₂/CF.

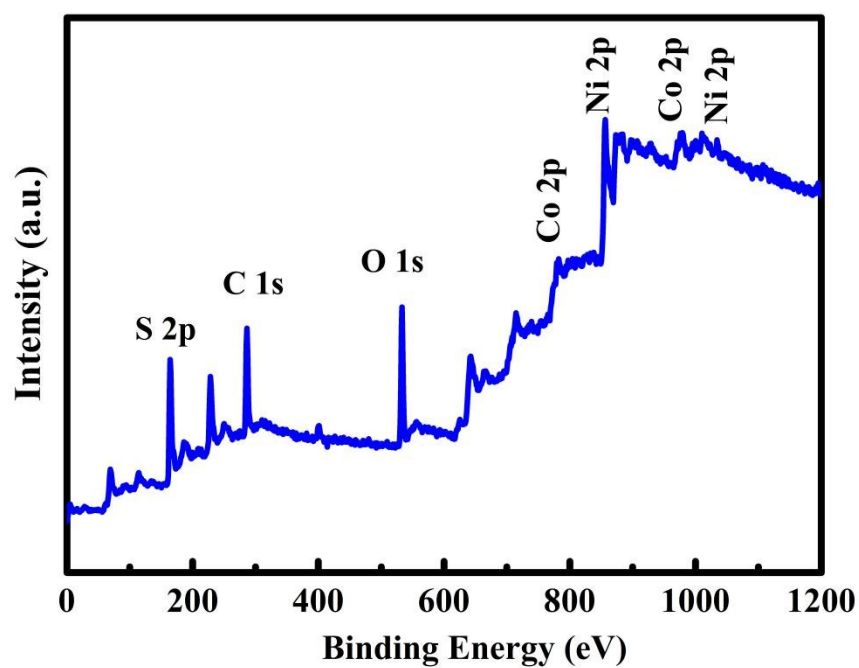


Fig. S5 XPS survey spectrum of the NiCo₂S₄@NiS/CF.

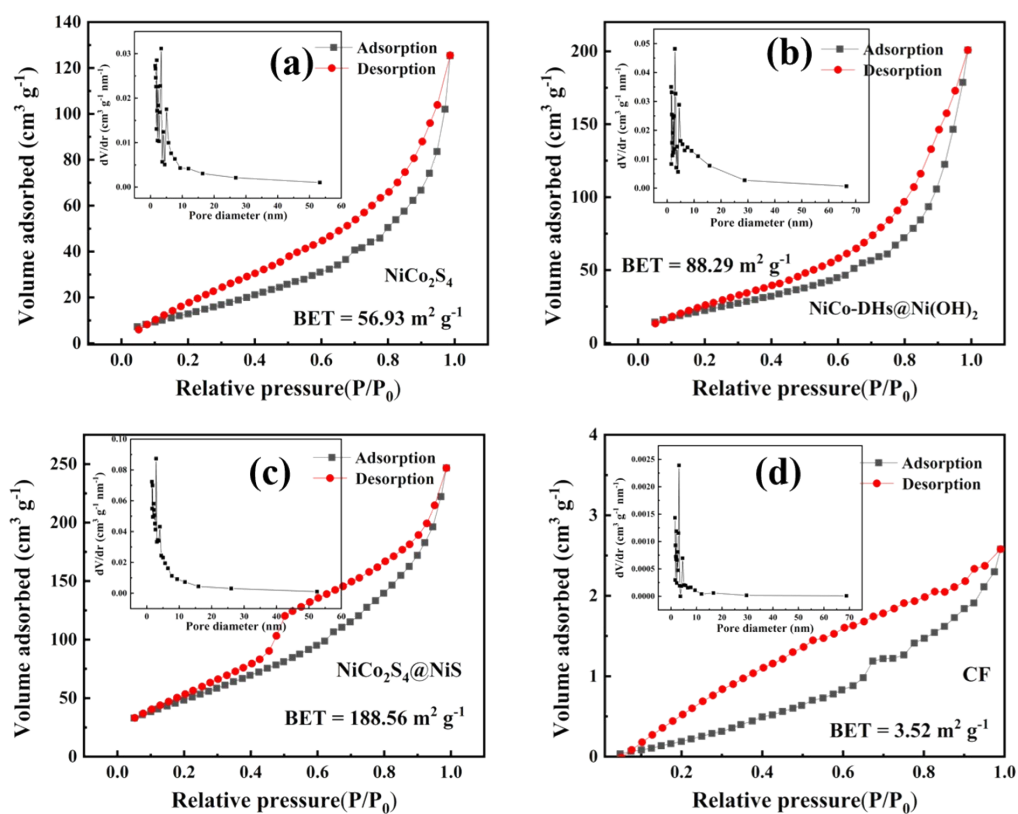


Fig. S6 XPS survey spectrum of the $\text{NiCo}_2\text{S}_4@\text{NiS}/\text{CF}$.

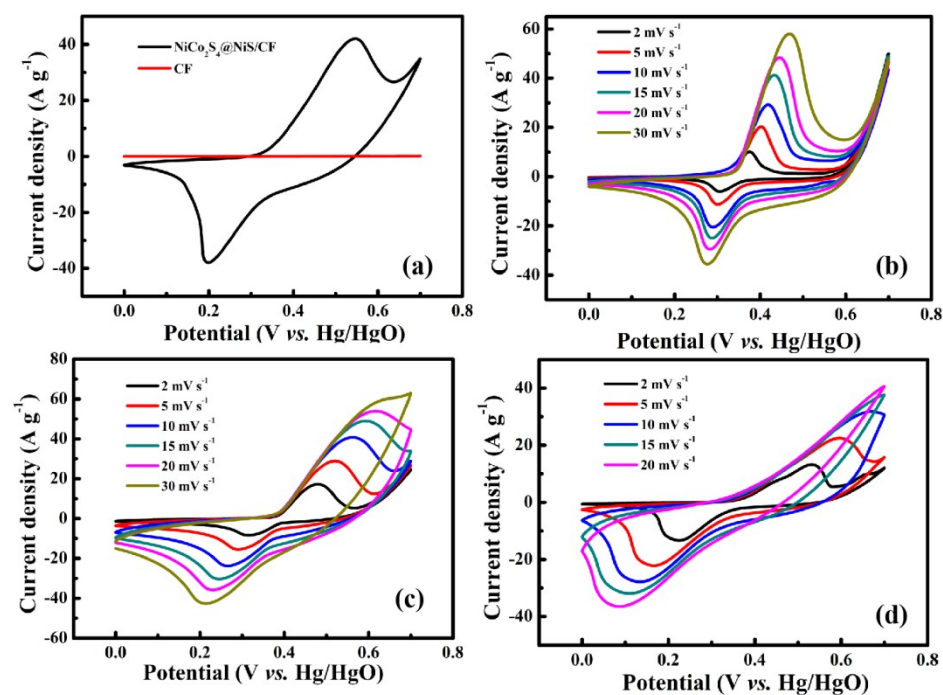


Fig. S7 (a) CV curves of $\text{NiCo}_2\text{S}_4@\text{NiS}/\text{CF}$ and pure CF at 10 mV s^{-1} ; CV curves at different scan rates: (b) $\text{NiCo}_2\text{S}_4/\text{CF}$; (c) NiS/CF ; (d) $\text{NiCo-DHs}@\text{Ni}(\text{OH})_2/\text{CF}$.

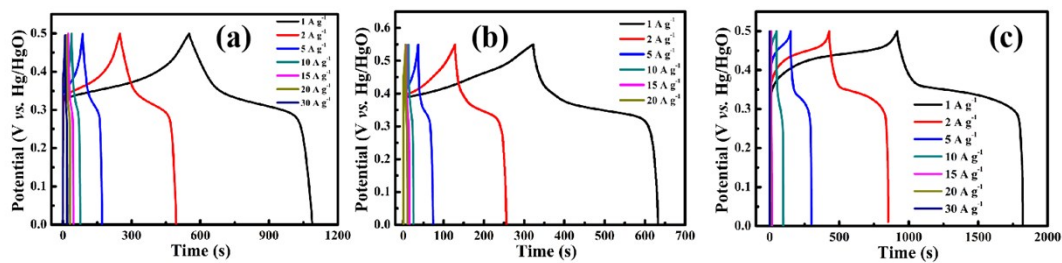


Fig. S8 GCD curves: (a) $\text{NiCo}_2\text{S}_4/\text{CF}$; (b) NiS/CF ; (c) $\text{NiCo-DHs}@\text{Ni}(\text{OH})_2/\text{CF}$.

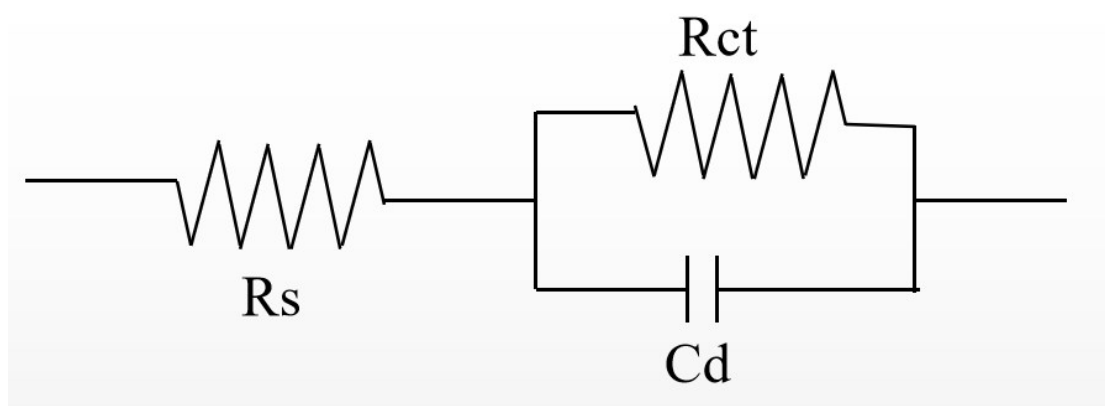


Fig. S9 Equivalent circuit image of EIS fitting.

Table S1. The EIS of NiCo₂S₄/CF, NiS/CF, NiCo-DHs@Ni(OH)₂/CF and NiCo₂S₄@NiS/CF simulation results

Electrodes	R_s (Ω)	R_{ct} (Ω)
NiCo ₂ S ₄ /CF	0.50	0.19
NiS/CF	0.69	0.13
NiCo-DHs@Ni(OH) ₂ /CF	0.95	0.29
NiCo ₂ S ₄ @NiS/CF	0.78	0.04

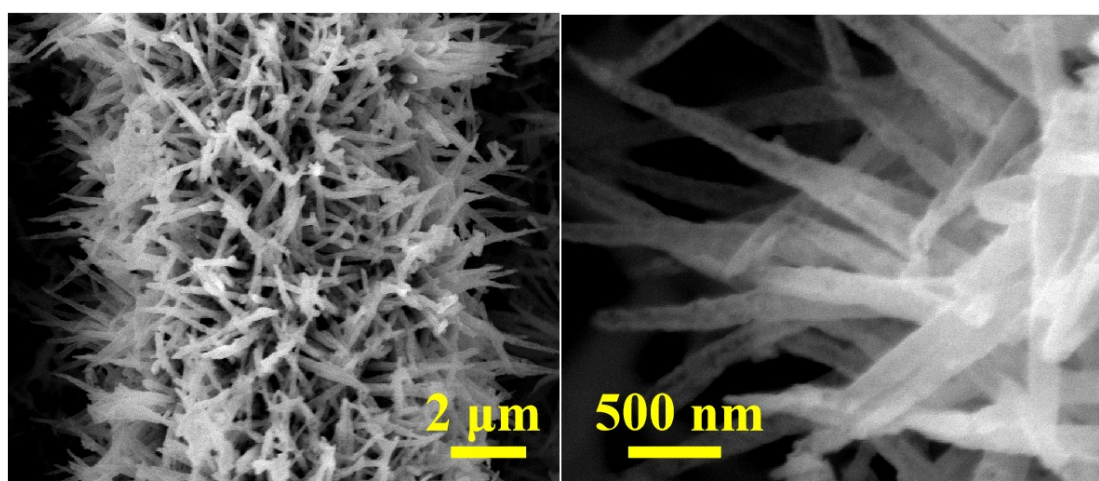


Fig. S10 SEM images of NiCo₂S₄@NiS/CF after 5000 cycles.

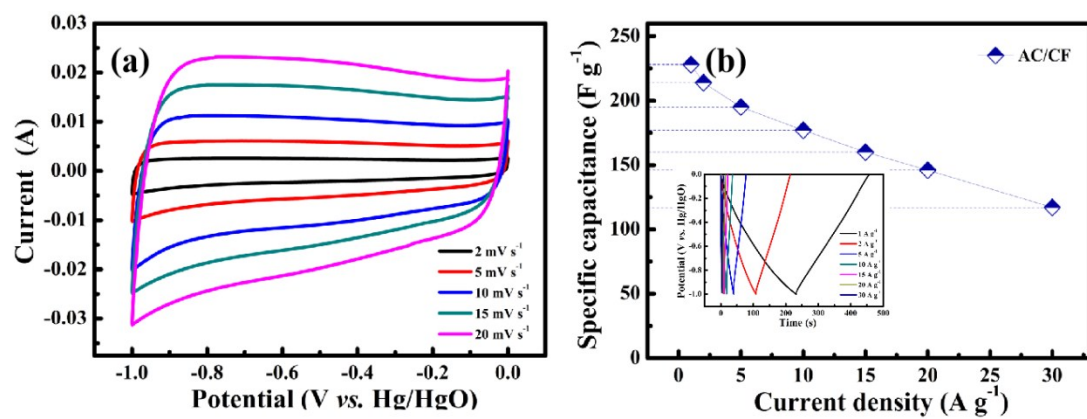


Fig. S11 (a) CV curves of the AC with different scan rates; (b) GCD curves of the AC with different current densities.

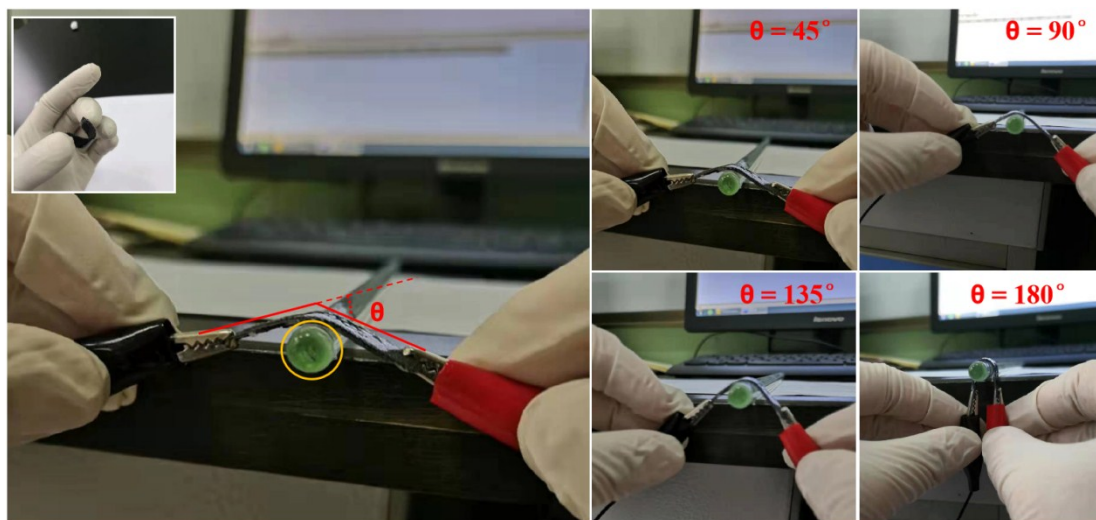


Fig. S12 Bending test equipment for all-solid-state NiCo₂S₄@NiS/CF//AC HSC.